

PUB-NO: DE010114410A1

DOCUMENT-IDENTIFIER: **DE 10114410 A1**

TITLE: Phase-noise waveform quality
measuring device e.g. for
analyzing clock signal,
determines instantaneous phase of
signal and removes linear
phase to obtain phase-noise
waveform

PUBN-DATE: October 31, 2001

INVENTOR-INFORMATION:

NAME

COUNTRY

YAMAGUCHI, TAKAHIRO

JP

SOMA, MANI

US

ISHIDA, MASAHIRO

JP

ASSIGNEE-INFORMATION:

NAME

COUNTRY

ADVANTEST CORP

JP

SOMA MANI

US

APPL-NO: DE10114410

APPL-DATE: March 23, 2001

PRIORITY-DATA: US53818600A (March 29, 2000)

INT-CL (IPC) : G01R029/02

EUR-CL (EPC) : G01R029/26

DERWENT-ACC-NO: 2002-123563

DERWENT-WEEK: 200504

COPYRIGHT 2006 DERWENT INFORMATION LTD

TITLE: Phase-noise waveform quality measuring device e.g. for analyzing clock signal, determines instantaneous phase of signal and removes linear phase to obtain phase-noise waveform

INVENTOR: ISHIDA, M; SOMA, M ; YAMAGUCHI, T

PATENT-ASSIGNEE: ADVANTEST KK [ADVAN] , SOMA M [SOMAI]

PRIORITY-DATA: 2000US-0538186 (March 29, 2000)

PATENT-FAMILY:

PUB-NO	PAGES	PUB-DATE	MAIN-IPC
JP 3609740 B2	016	January 12, 2005	G01R 029/02
DE 10114410 A1		October 31, 2001	
N/A	019	G01R 029/02	
JP 2001337121 A		December 7, 2001	
N/A	012	G01R 029/02	
US 6735538 B1		May 11, 2004	
N/A	000	G01R 029/26	

APPLICATION-DATA:

PUB-NO	APPL-DESCRIPTOR	APPL-
NO	APPL-DATE	

JP 3609740B2	N/A
2001JP-0091965	March 28, 2001
JP 3609740B2	Previous Publ.
JP2001337121	N/A
DE 10114410A1	N/A
2001DE-1014410	March 23, 2001
JP2001337121A	N/A
2001JP-0091965	March 28, 2001
US 6735538B1	N/A
2000US-0538186	March 29, 2000

INT-CL (IPC): G01R029/02, G01R029/26

ABSTRACTED-PUB-NO: DE 10114410A

BASIC-ABSTRACT:

NOVELTY - The device includes an analysis signal transformation device for transforming an input signal into a complex analysis signal. An instantaneous phase estimator determines the instantaneous phase of the analysis signal. A linear phase removal device removes the linear phase from the instantaneous phase of the analysis signal to obtain a phase-noise waveform. A quality measurement estimator determines a measure of quality of the phase-noise waveform.

DETAILED DESCRIPTION - An INDEPENDENT CLAIM is included for a method of measuring the quality of a phase-noise waveform.

USE - E.g. for measuring the quality (such as the

amount of jitter) of a clock signal driving a microprocessor.

ADVANTAGE - Allows measurement of quality of a phase-noise waveform.

DESCRIPTION OF DRAWING(S) - The drawing is a diagram representing period jitter.

CHOSEN-DRAWING: Dwg.1A/10

DERWENT-CLASS: S01 U22

EPI-CODES: S01-D06; U22-D02C;